

Expecting the unknown...

# A preliminary characterization of 3D silicon sensors by means of IV-CV measurements



CERN Internship: April 2015

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SSD/ PH-DT-DD

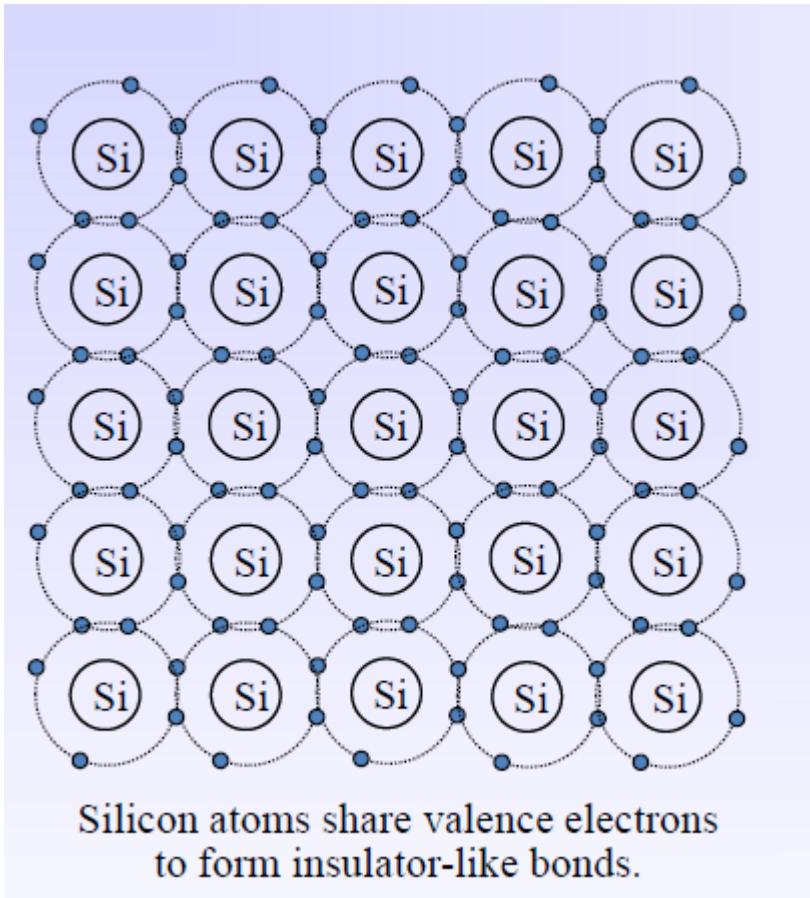


# Outline



- **Silicon sensors**– The physics behind it
- **IV and CV** – The theoretical, ideal curve
- **My measurements** – The Setup
- **My results** – The experimental reality
- **Review on the internship** – What's left to say

# The chemistry behind a semiconductor... Silicon sensors



	II	III	IV	V	VI
2	9,0 Be 4	10,8 B 5	12,0 C 6	14,0 N 7	16,0 O 8
3	24,3 Mg 12	27,0 Al 13	28,1 Si 14	31,0 P 15	32,1 S 16
4	40,1 Ca 20	69,7 Ga 31	72,6 Ge 32	74,9 As 33	79,0 Se 34
5	87,6 Sr 38	114,8 In 49	118,7 Sn 50	121,8 Sb 51	127,6 Te 52
6	137,3 Ba 56	204,4 Tl 81	207,2 Pb 82	209,0 Bi 83	209 Po 84

Introduction

Silicon sensors

Measurement Setup

IV and CV theory

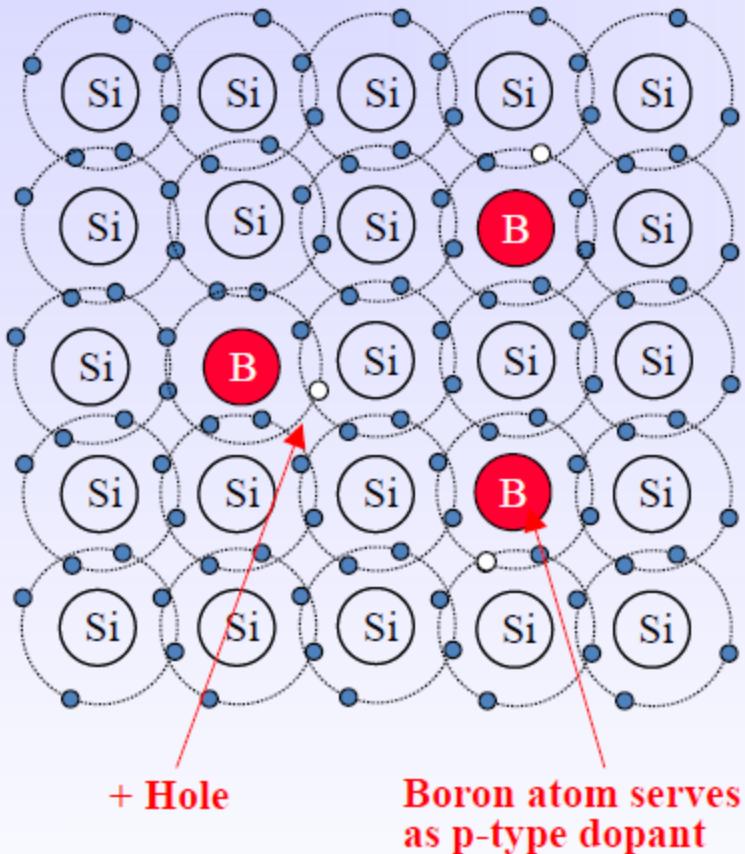
Measurement results

Review

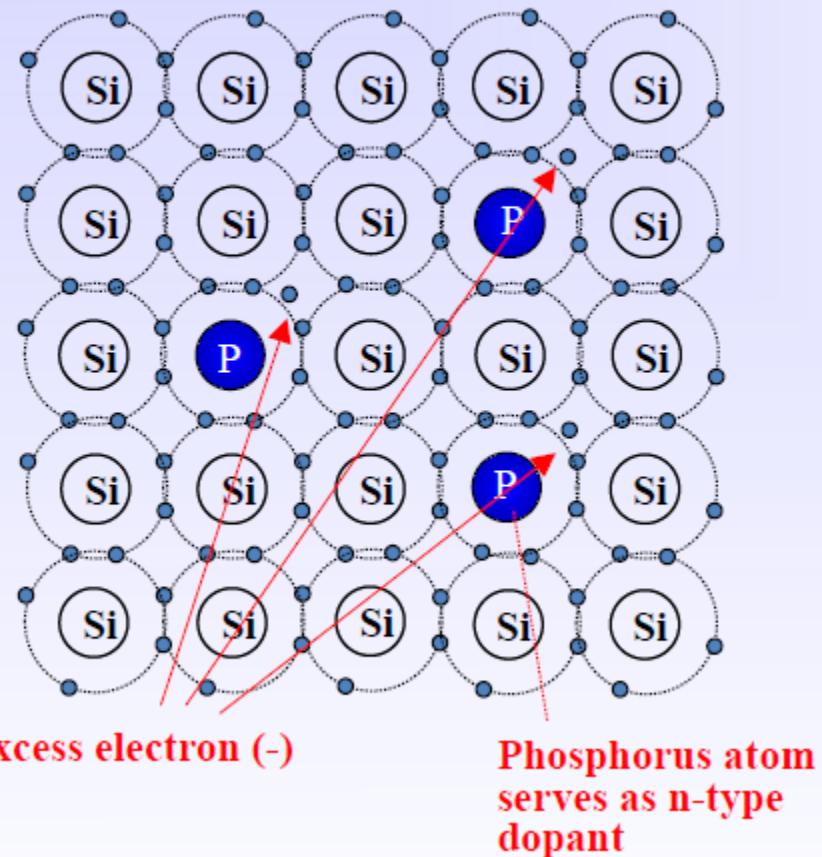
# The chemistry behind a semiconductor... Silicon sensors



Acceptor atoms provide a deficiency of electrons to form p-type silicon.



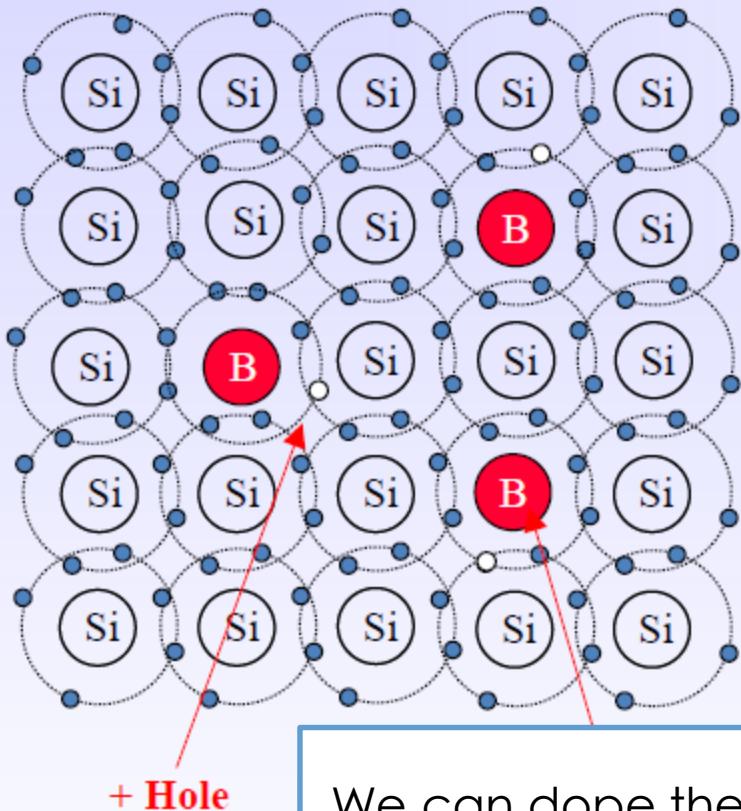
Donor atoms provide excess electrons to form n-type silicon.



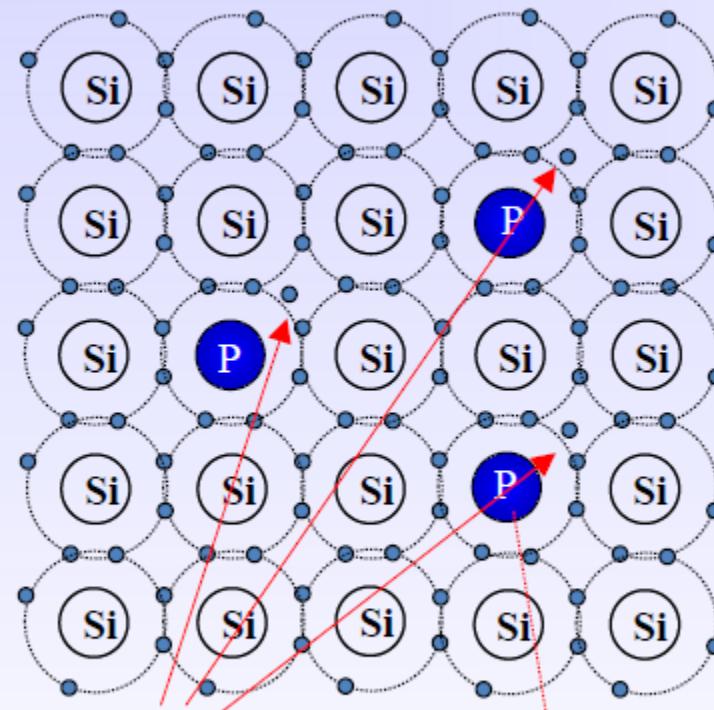
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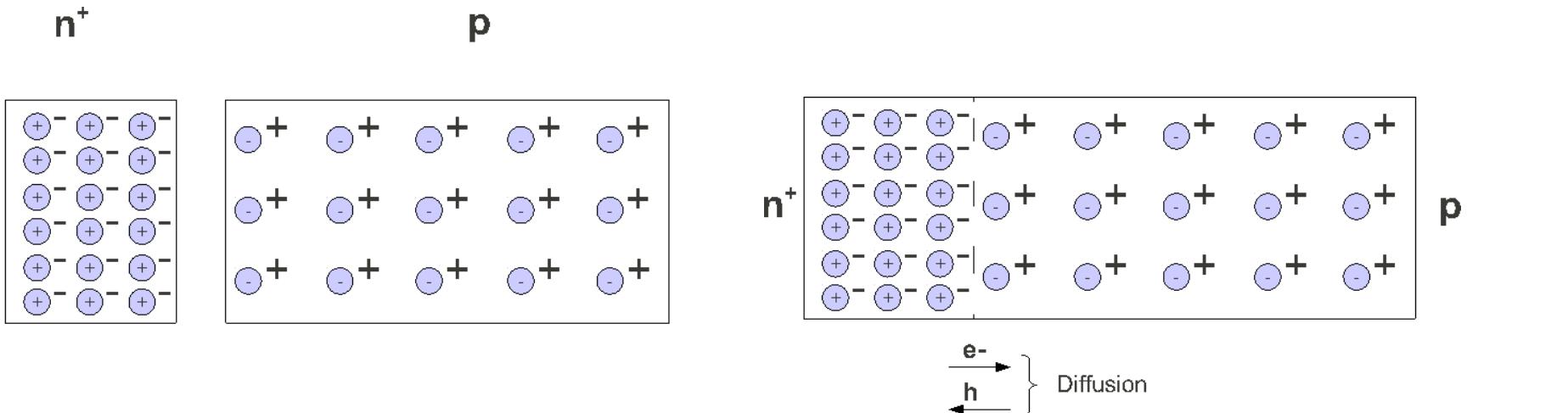
Donor atoms provide excess electrons to form n-type silicon.



We can dope the Si negatively or quasi positively.

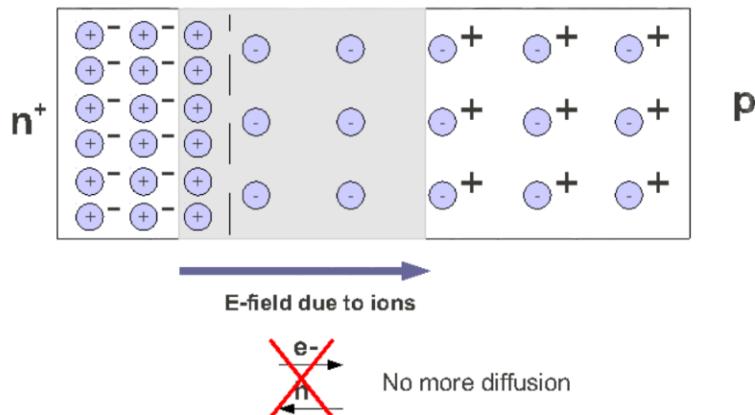
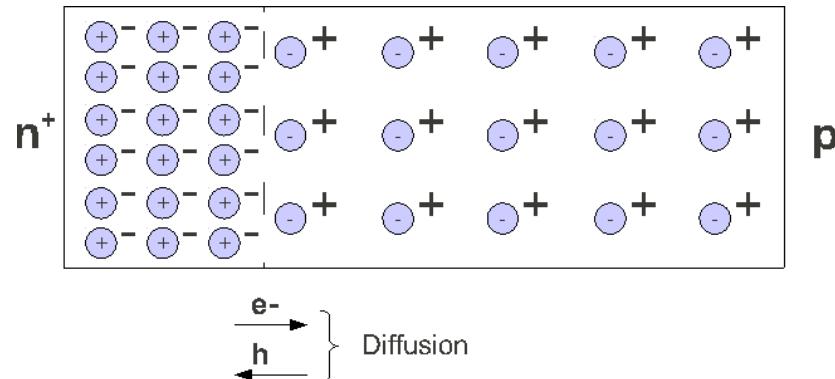
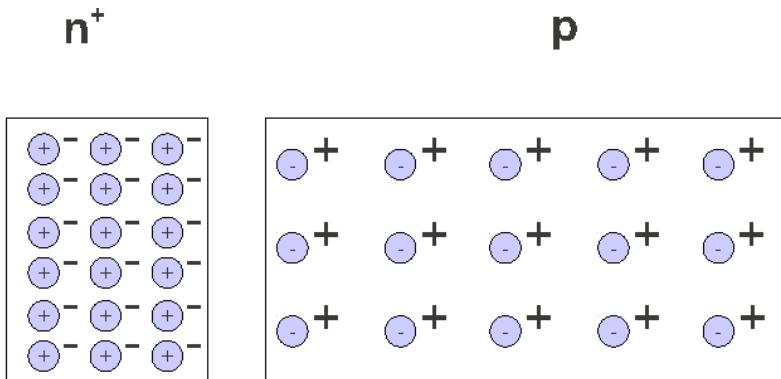
phorus atom  
es as n-type  
nt

# The 2D physics behind a semiconductor... Silicon sensors



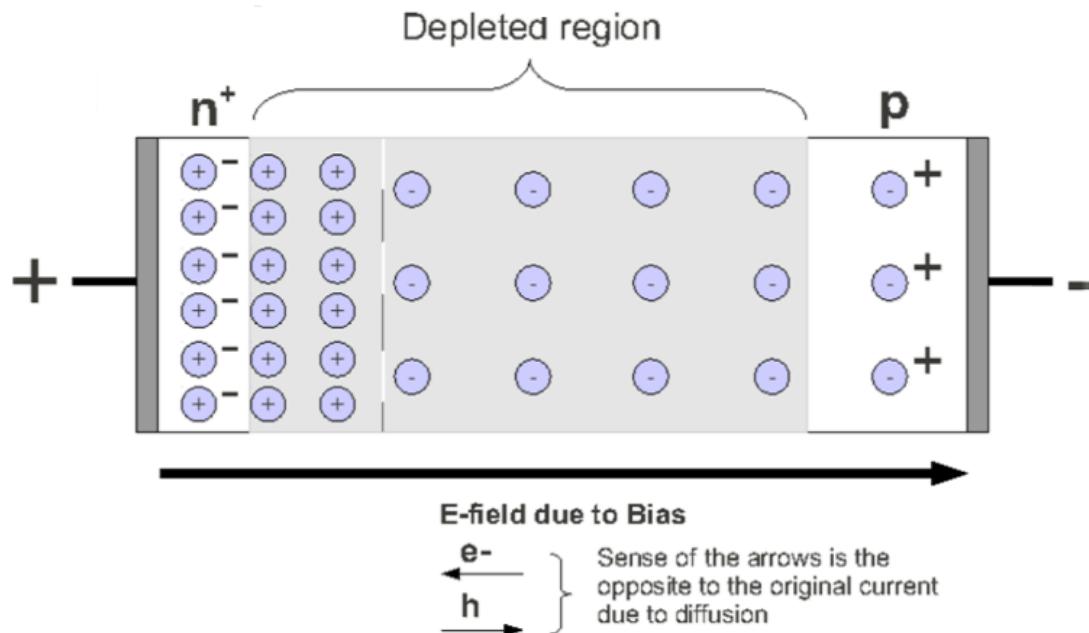
The two doped materials diffuse and the electrons fill the free holes.

# The 2D physics behind a semiconductor... Silicon sensors



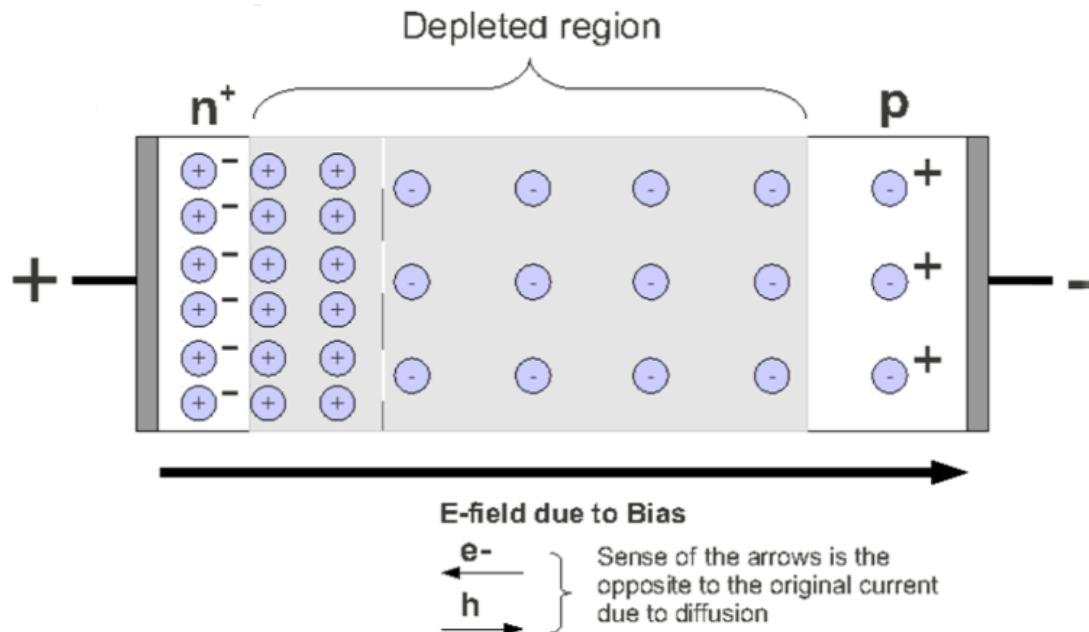
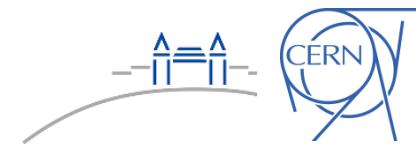
The diffusion has created an E-field, therefore the electron movement is stopped and the forces equalise each other.

# The 2D physics behind a semiconductor... Silicon sensors



By applying a voltage we can increase the E-field and thus increase the width of the depletion to a fixed maximum.

# The 2D physics behind a semiconductor... Silicon sensors

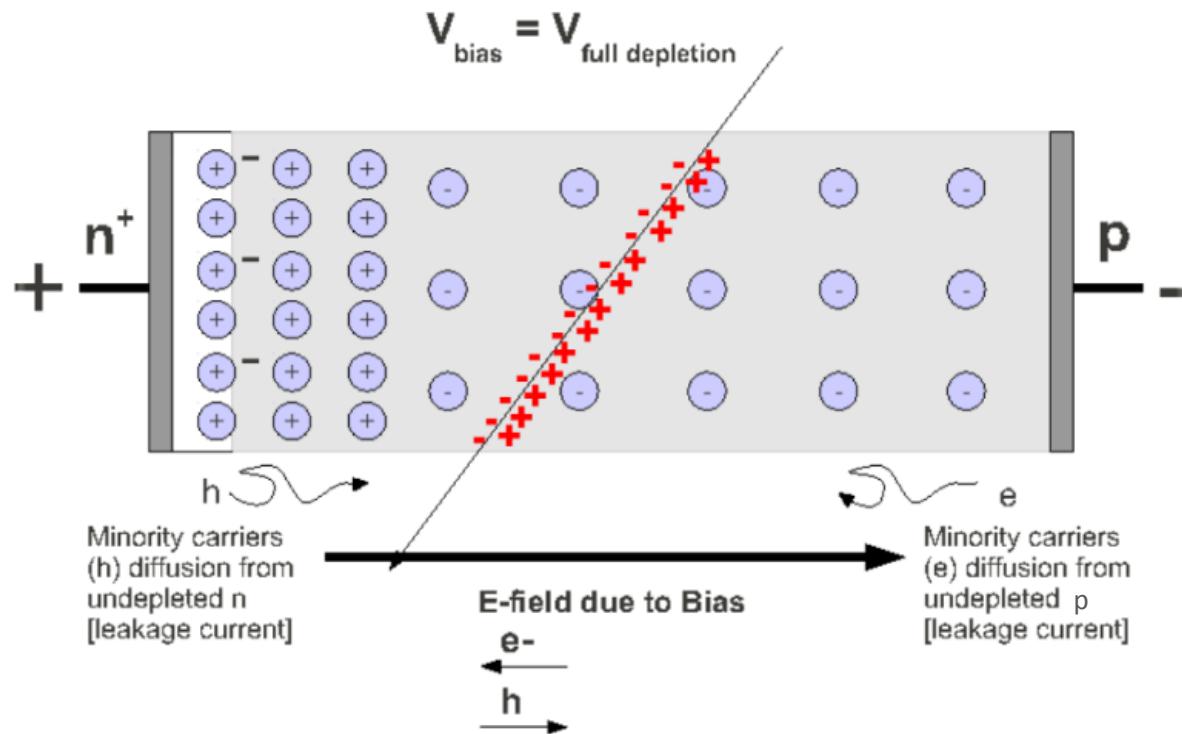


By applying a voltage we can increase the E-field and thus increase the width of the depletion to a fixed maximum.

1) The sensors can also be seen as a **capacitor** of variable thickness (as a function of V).

2) And a silicon sensor also is a diode.

# The 2D physics behind a semiconductor... Silicon sensors

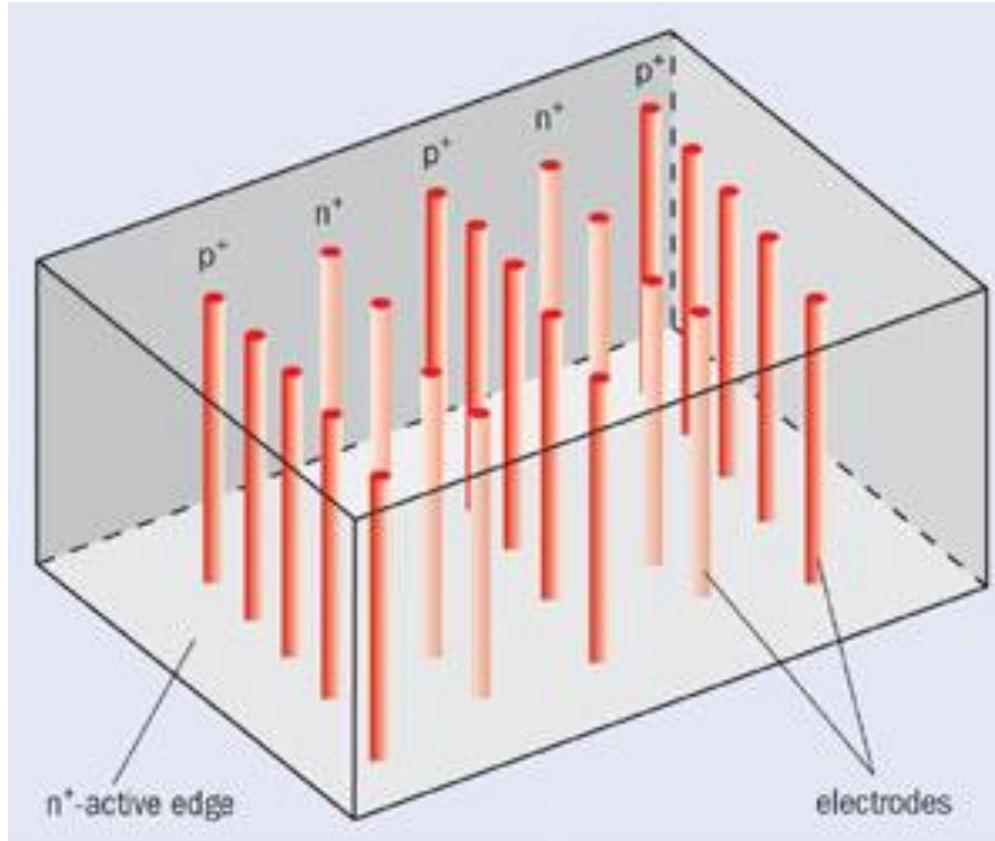


An ionising particle that passes the silicon sensor can be detected by the current it creates.

The aim is to keep the leakage current low.

# The 3D visualisation

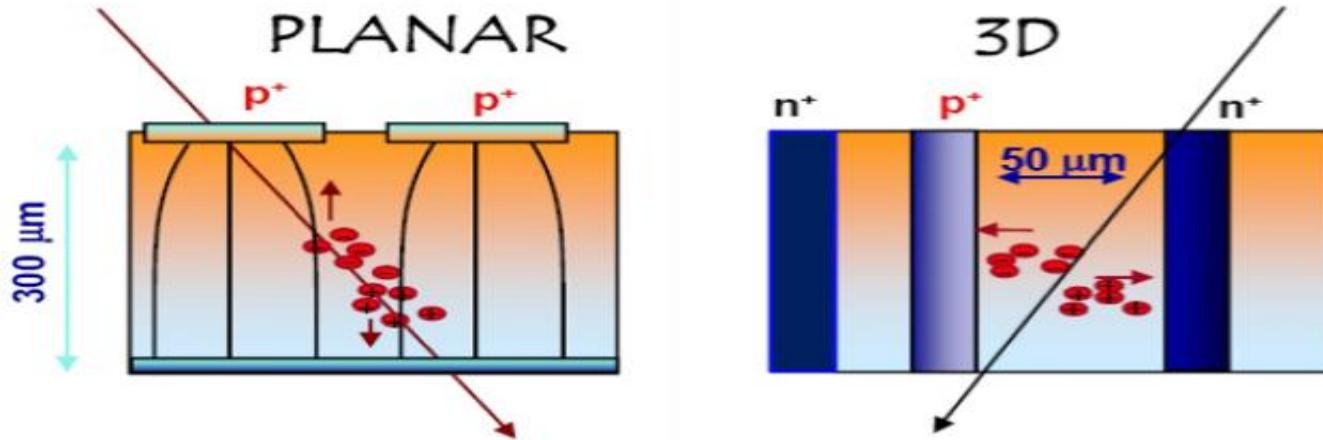
## Silicon sensors



A 3D-sensor shows the same attributes as the 2D.

# What dimension should it be?

## Silicon sensors



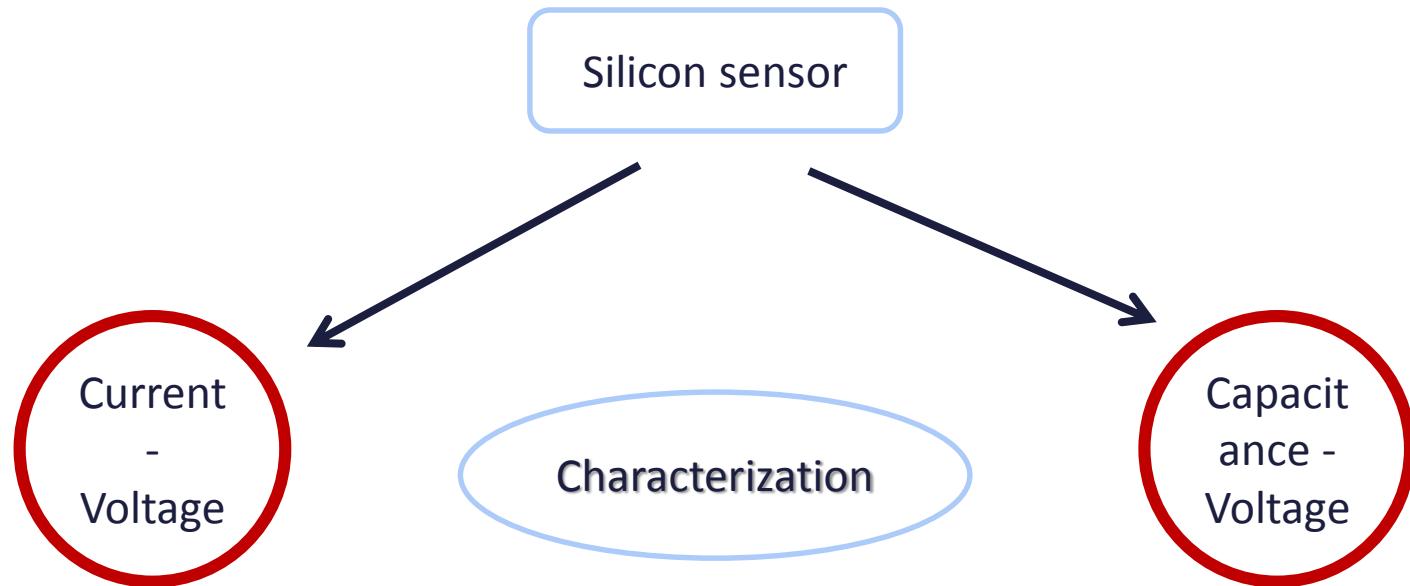
3Ds offer a faster charge collection  
Smaller depletion voltage  
& are radiation harder

BUT planar technology is the more consolidated

Both sensors show reasonable advantages.

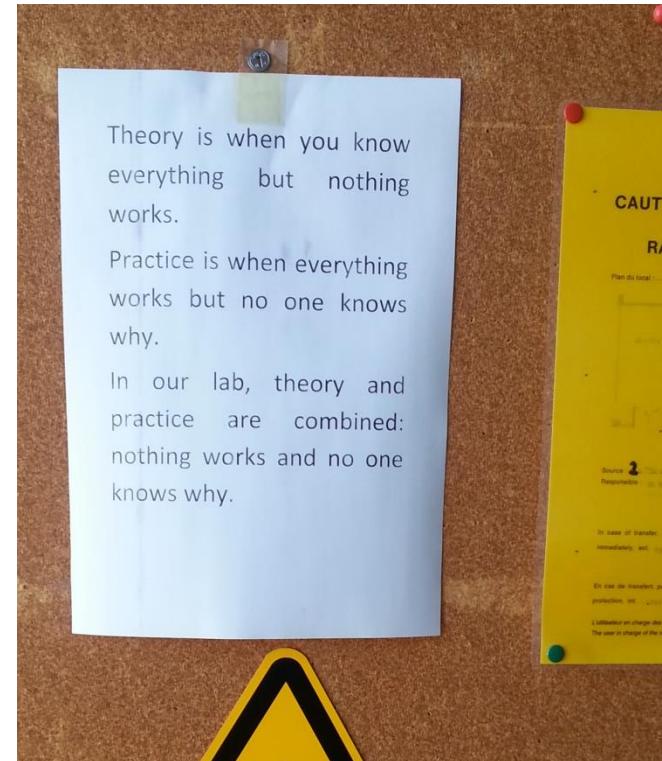
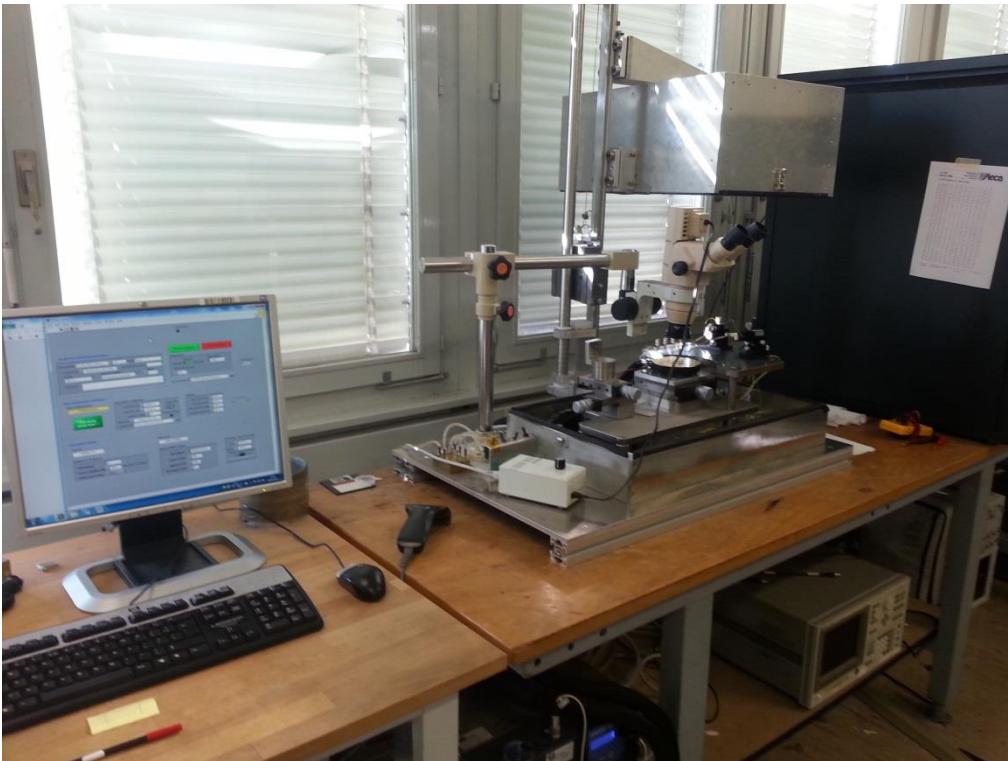
# What are IV and CV measurements?

## IV and CV theory



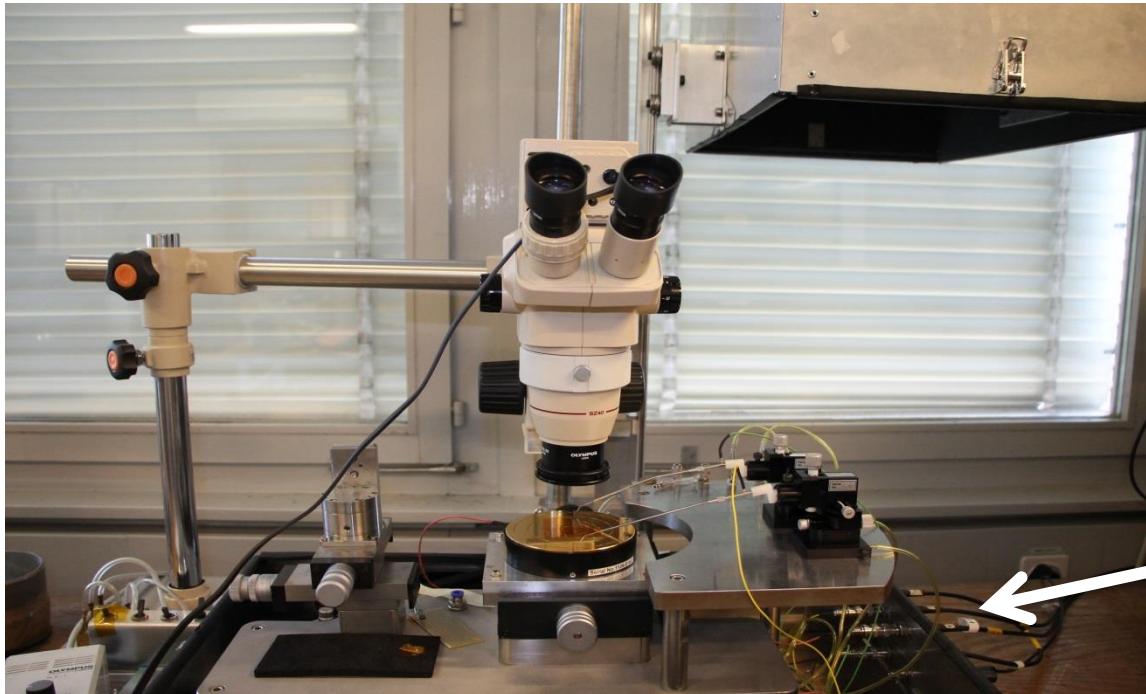
# The lab: My place to be

## Measurement-Set up



# The lab: My place to be

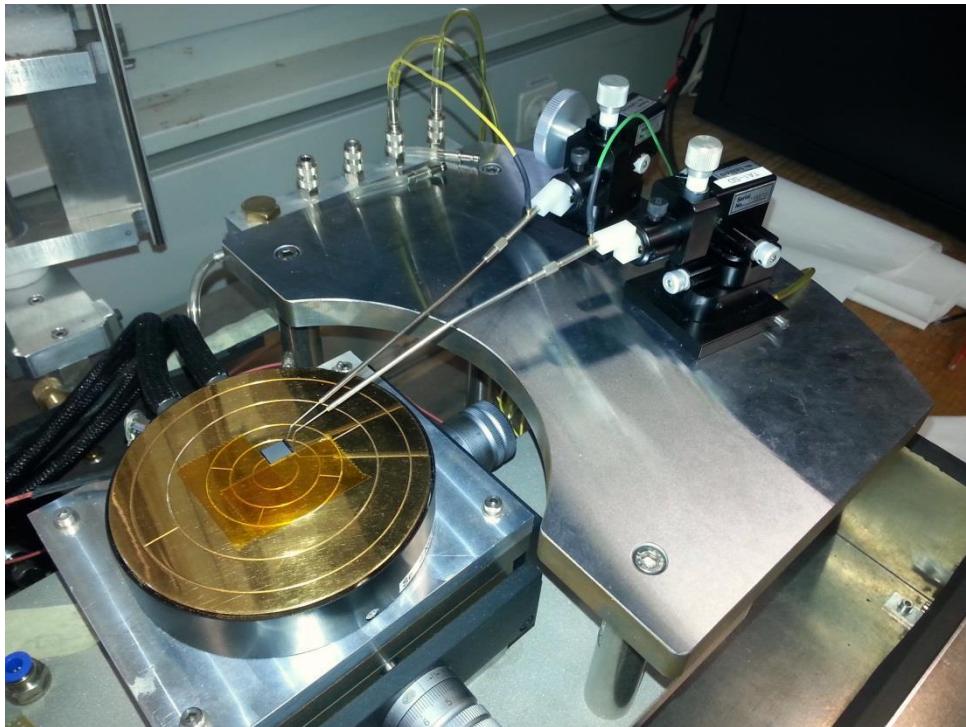
## Measurement-Set up



We apply a voltage and measure I or C.

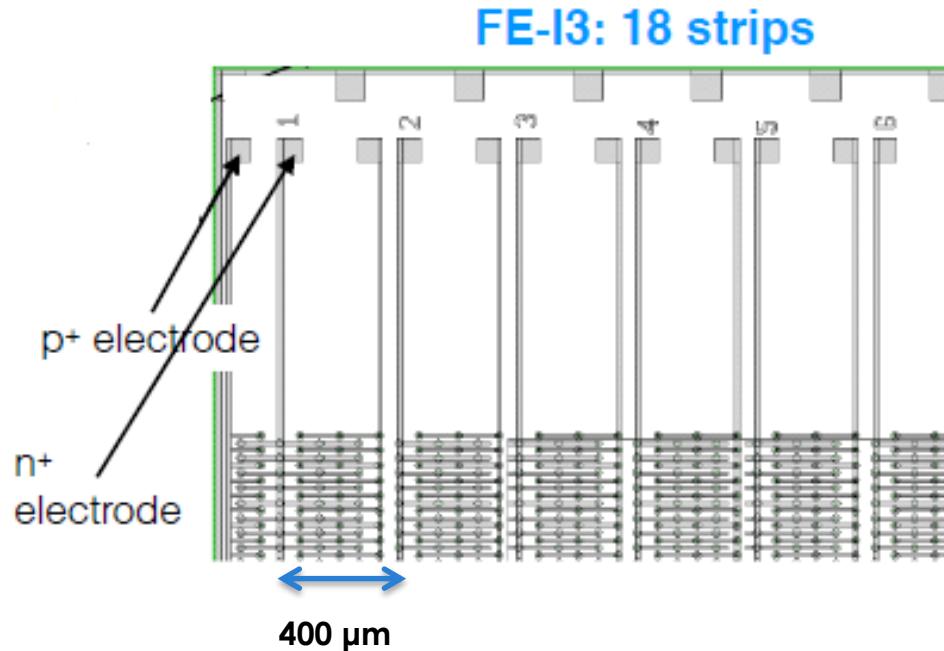
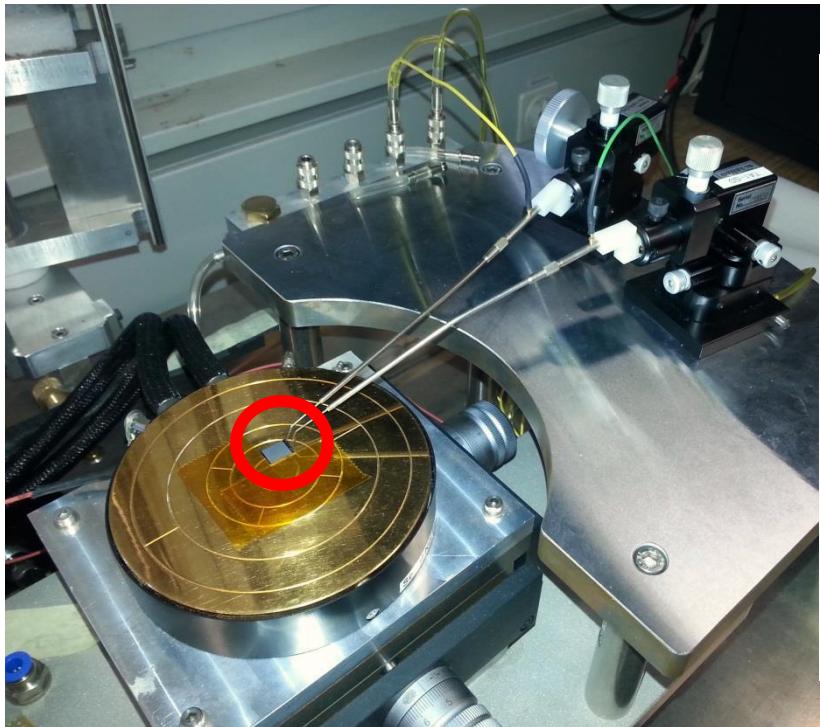
# Close-up: Microscope & sensitivity needed

## Measurement-Set up



# Close-up: Microscope & sensitivity needed

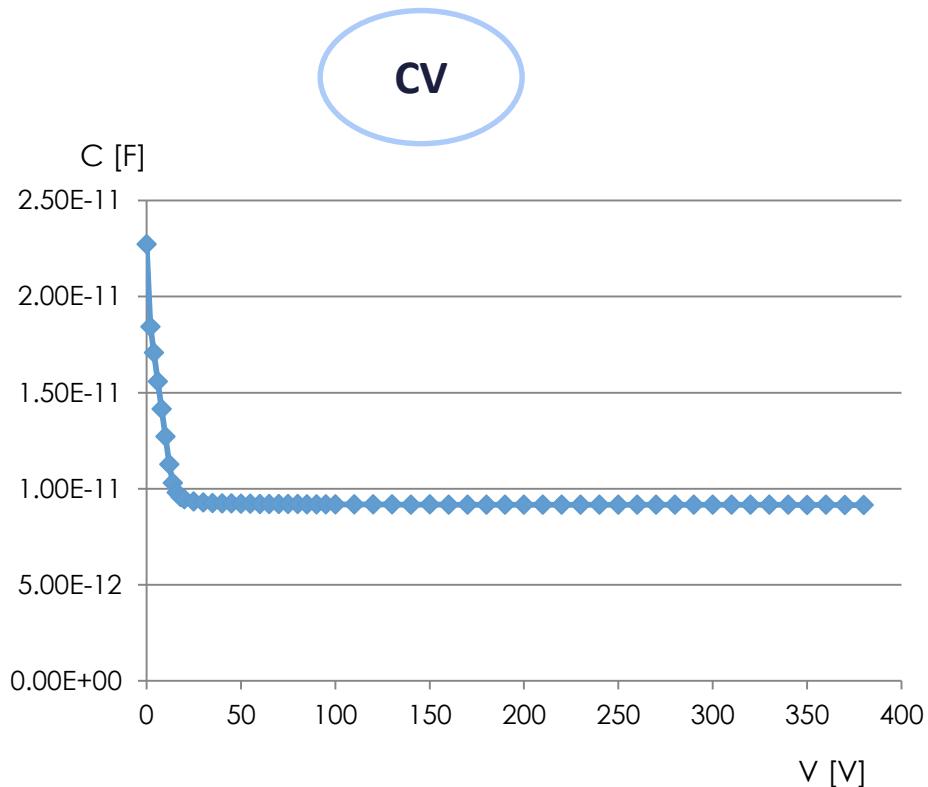
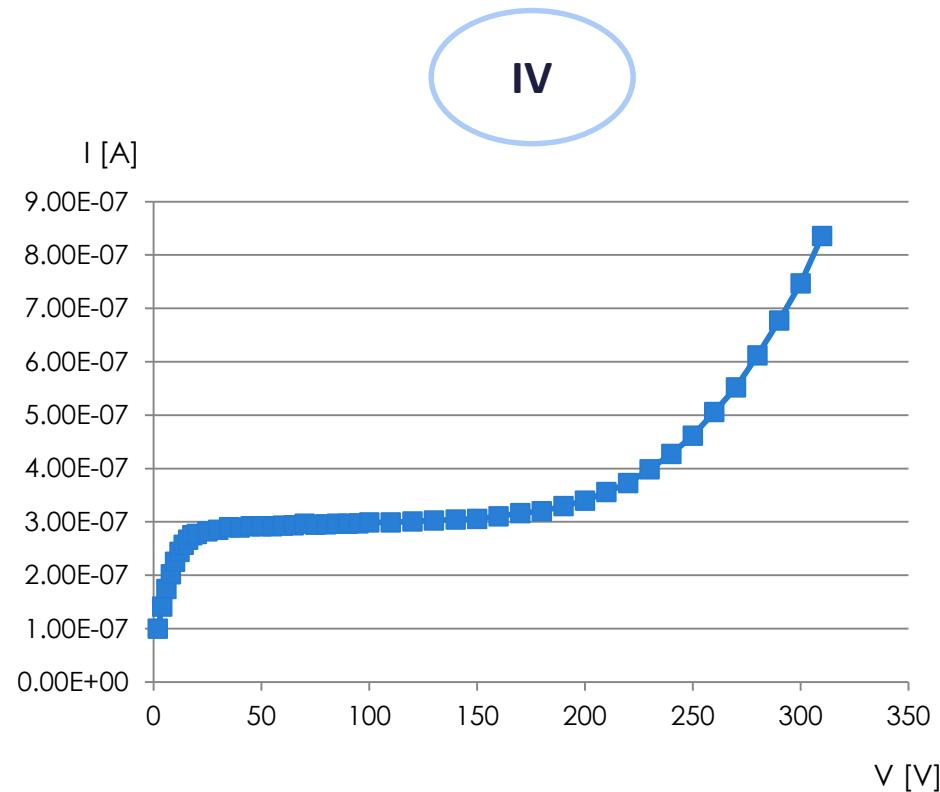
## Measurement-Set up



Connecting both needles is precision work.

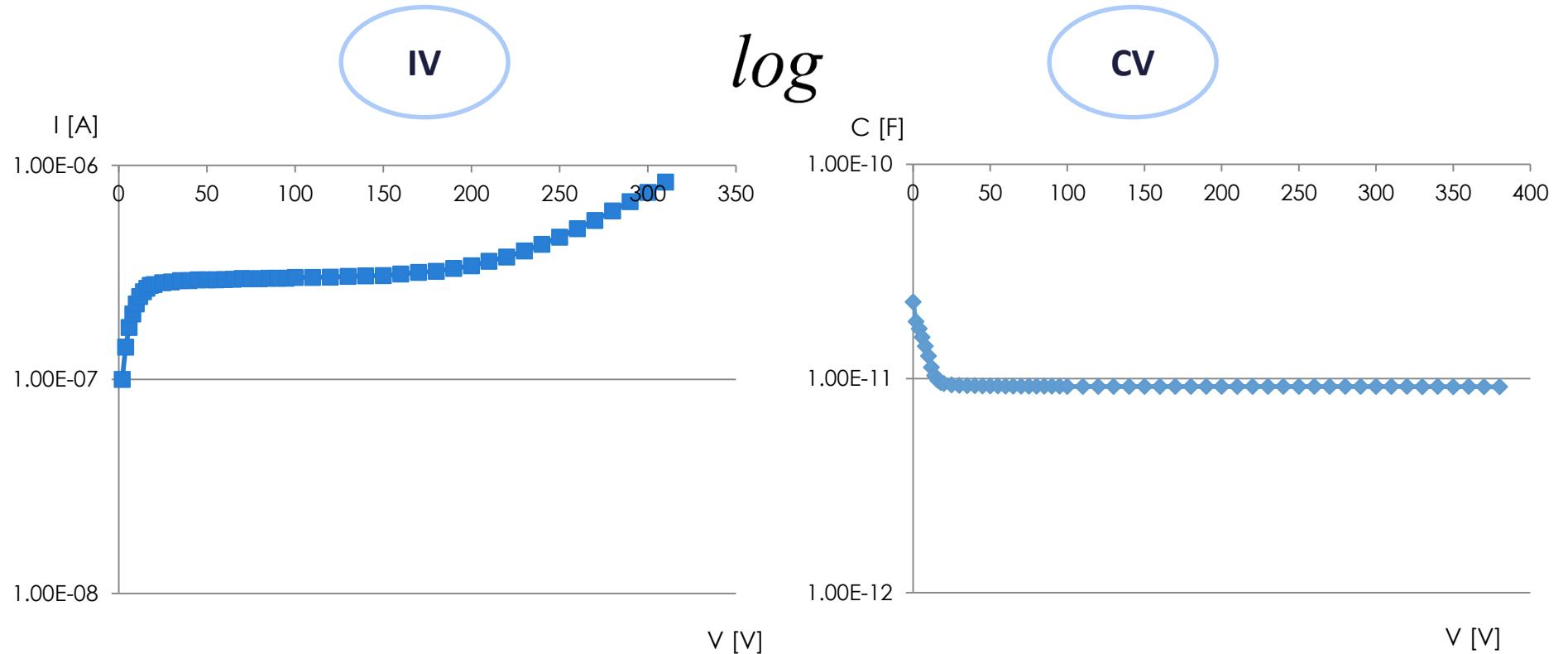
# What are IV and CV measurements?

## IV and CV theory



# What are IV and CV measurements?

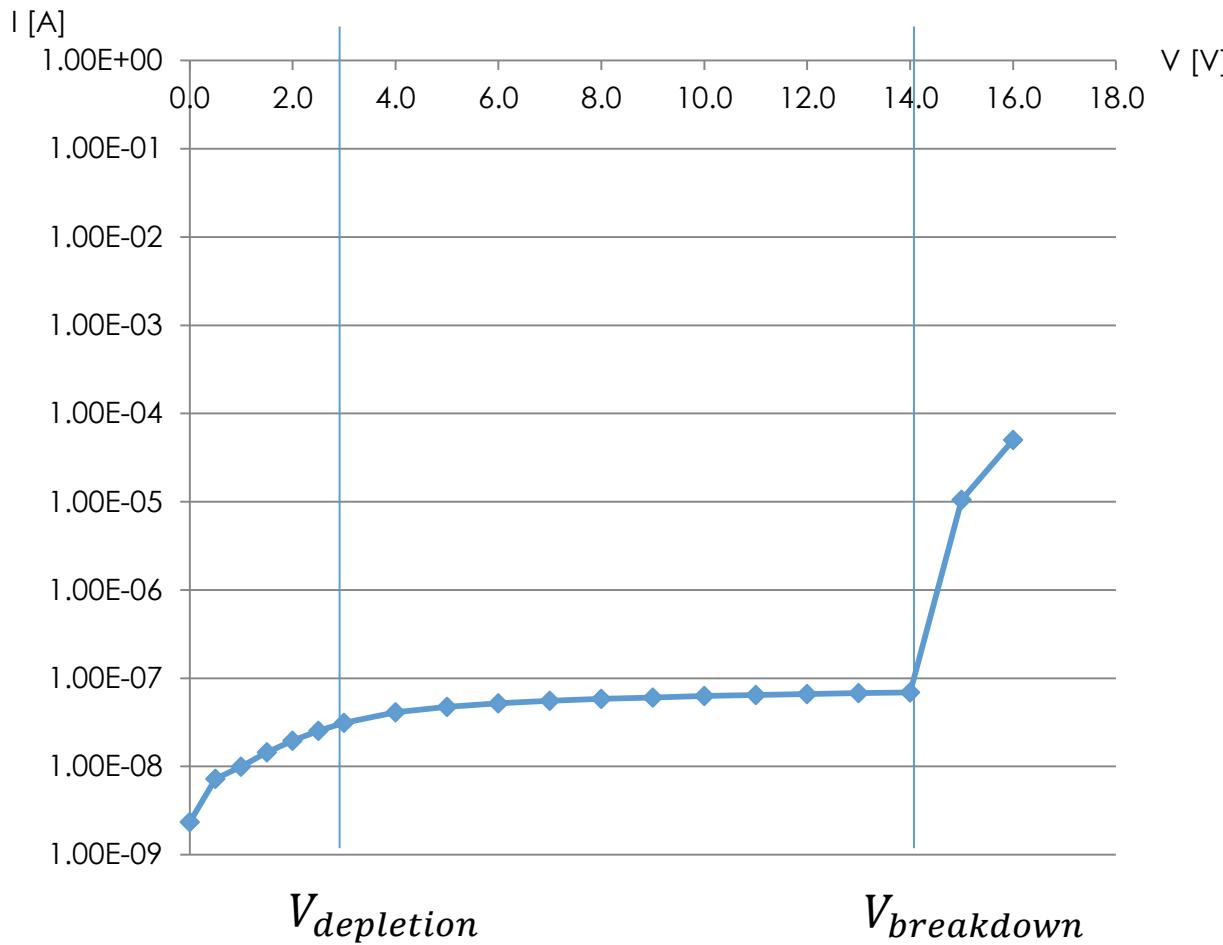
## IV and CV theory



The depletion and breakdown voltages are important properties.

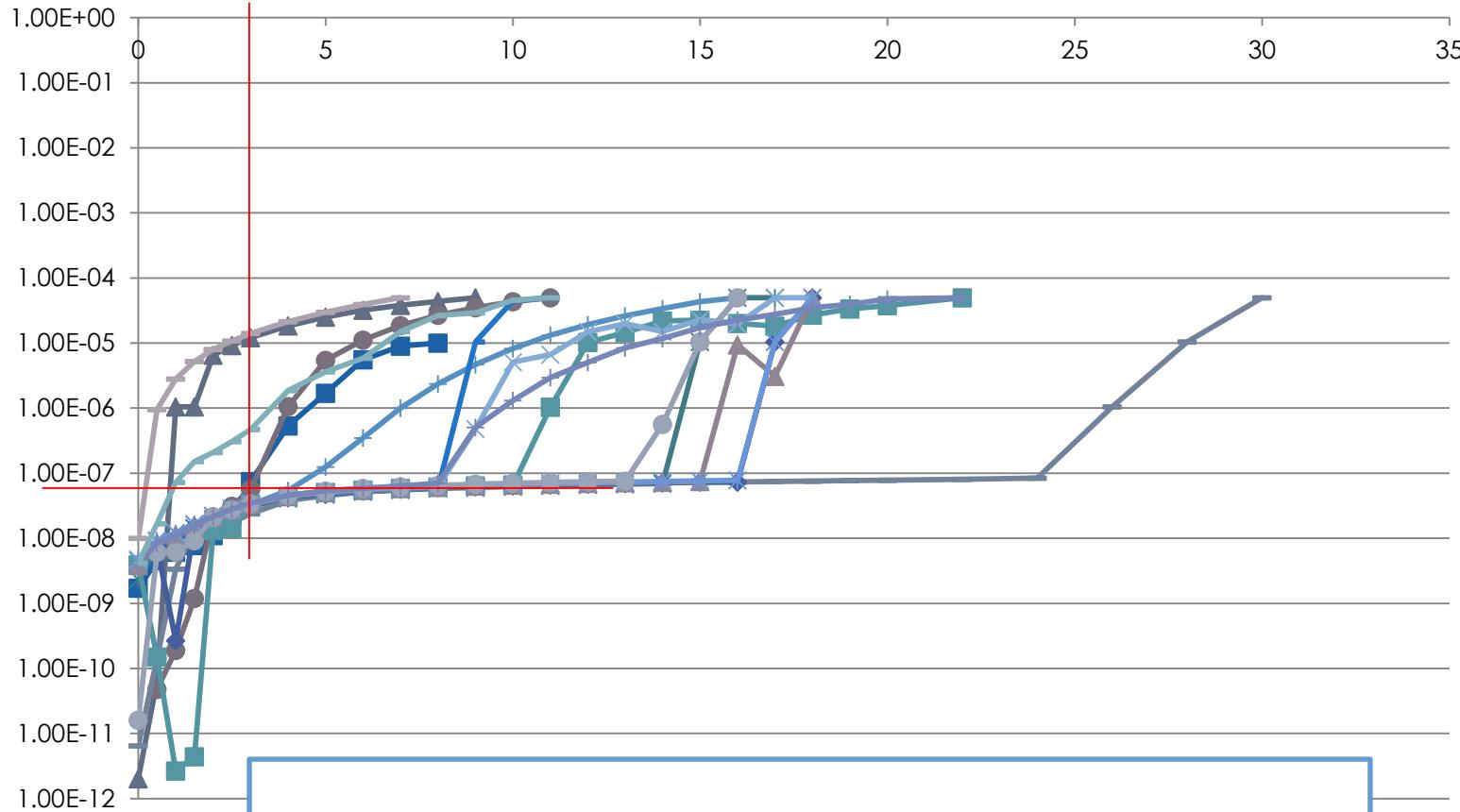
# The 3D-IV result for one single strip

## Measurement results



# Overlapping strips create confusion

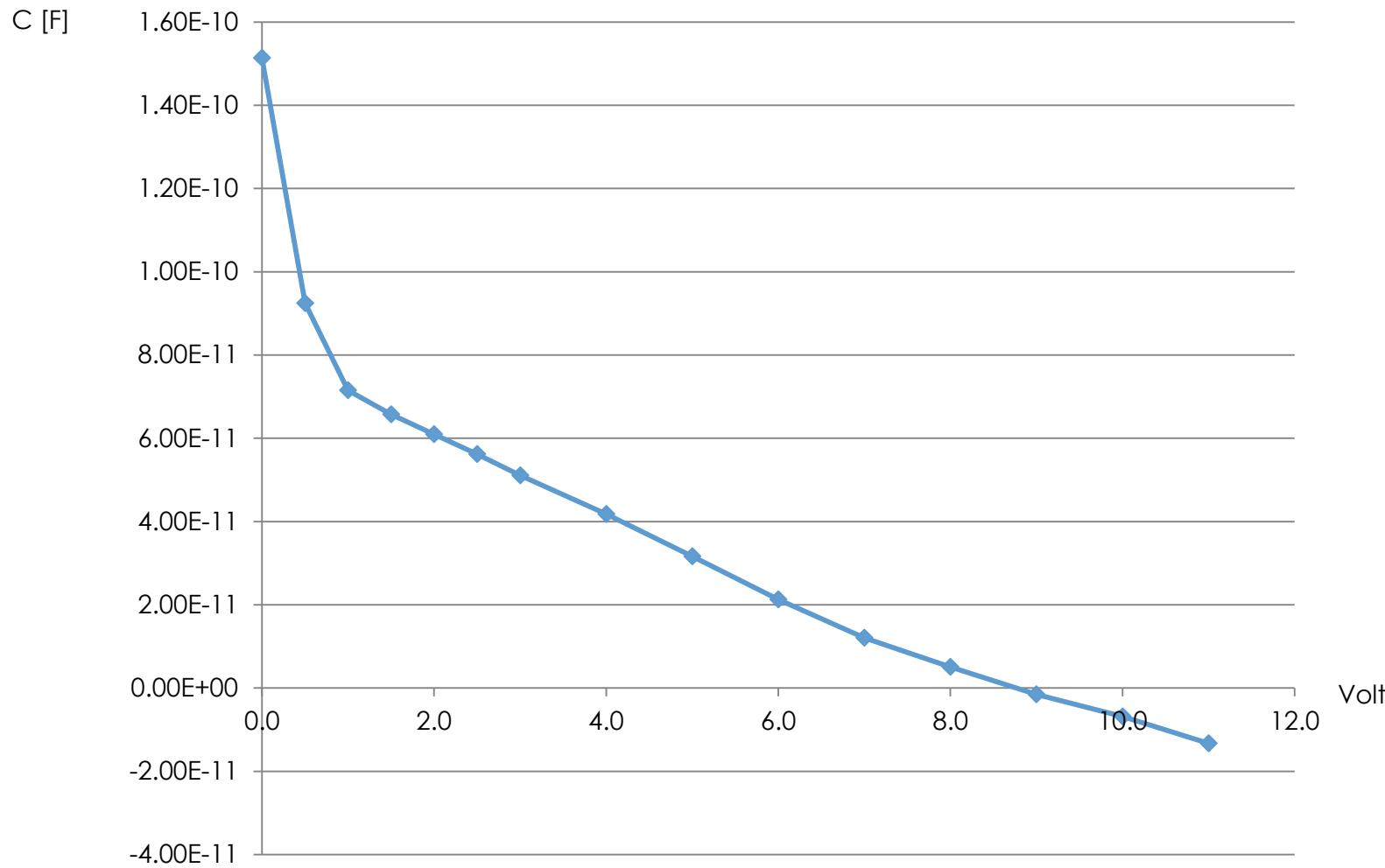
## Measurement results



No uniformity makes it a rather bad sensor.

# The 3D-CV result for one single strip

## Measurement results



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Silicon sensors

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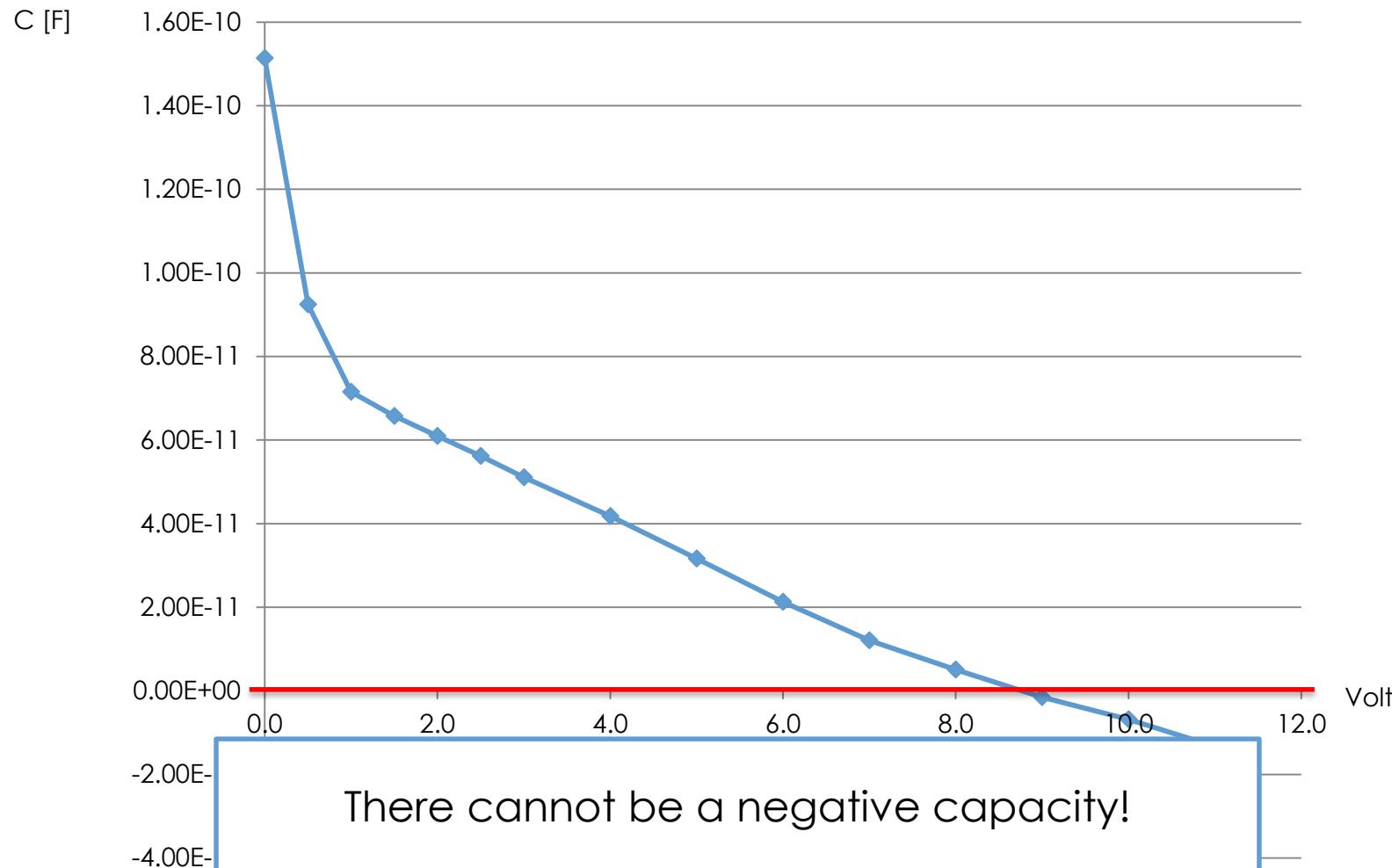
IV and CV theory

Measurement results

Review

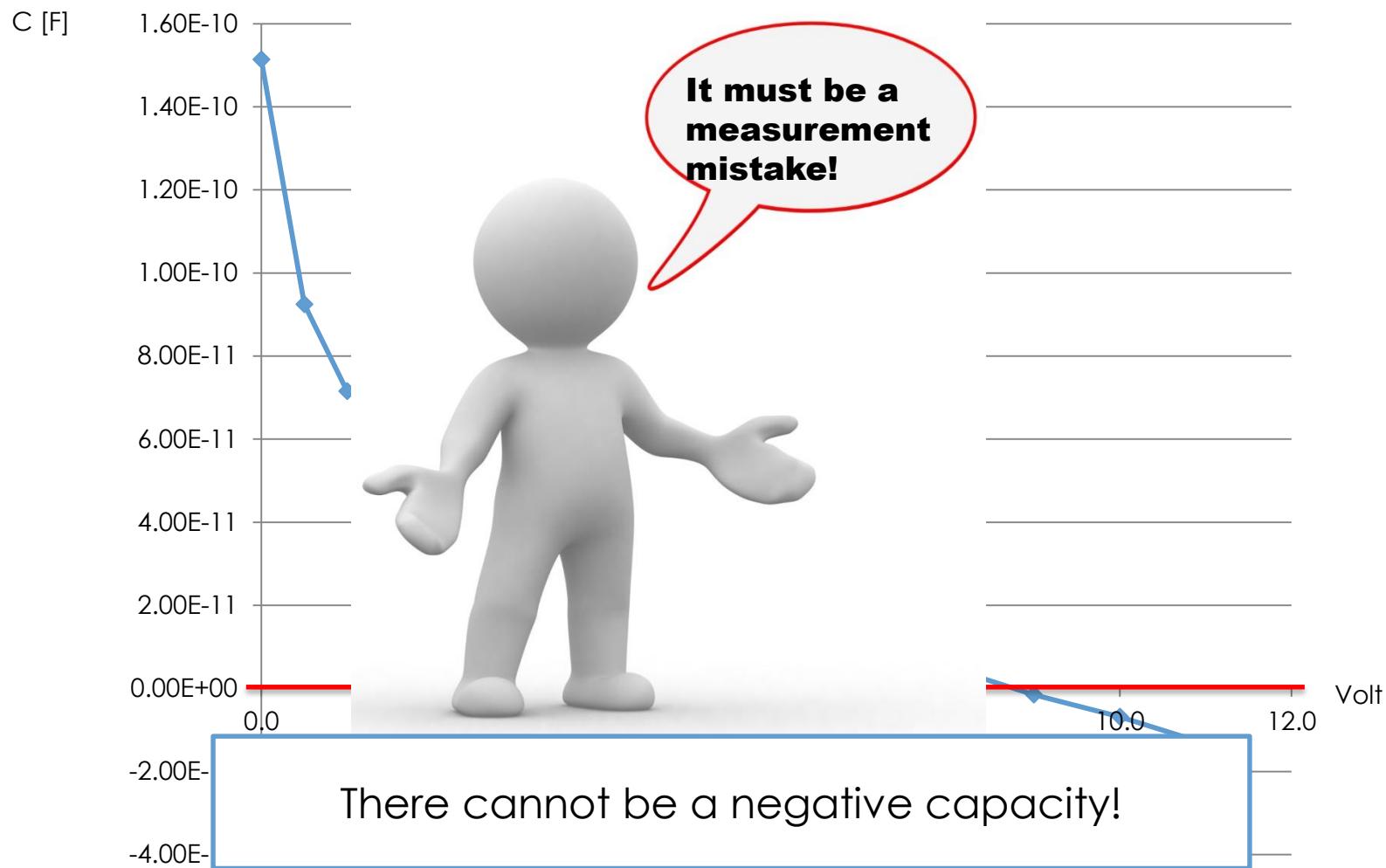
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## Measurement results



# The 3D-CV result for one single strip

## Measurement results



# Capacitance and its use...

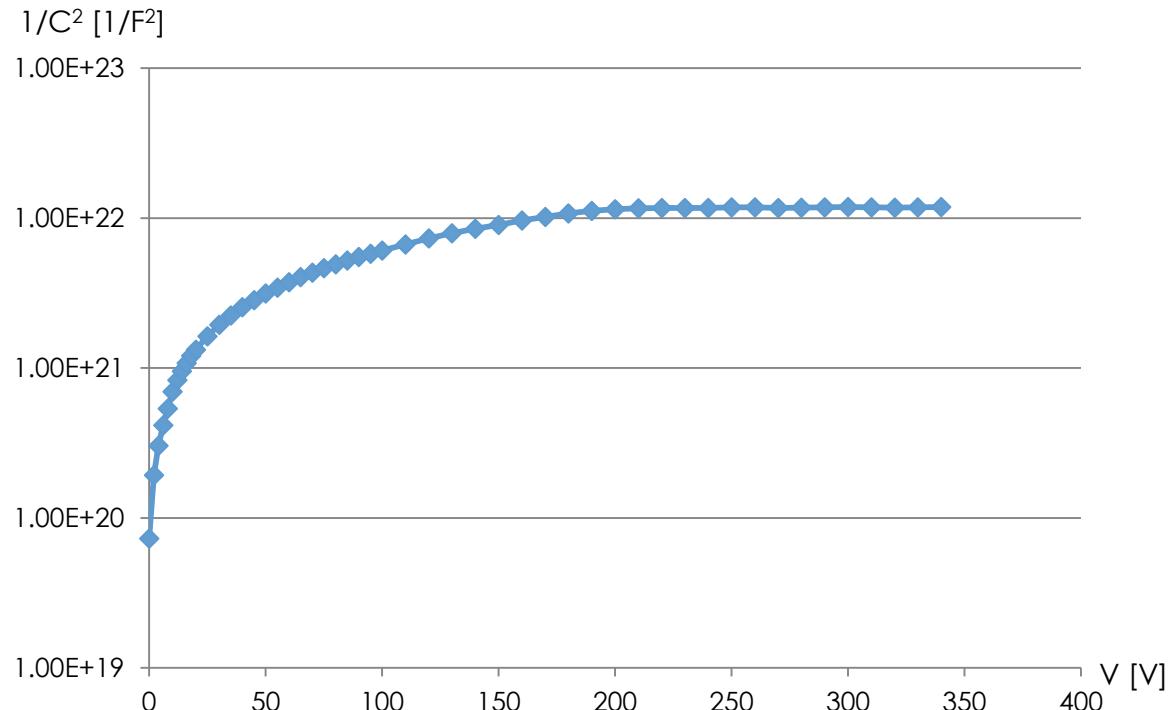
## Measurement results



$$C = \frac{\epsilon_0 \epsilon_r S}{d}$$

$$w = \sqrt{\left(\frac{2\epsilon_0 \epsilon_{si}}{e|N_{eff}|} V\right)}$$

If  $V = V_{depl}$  then  $w = d$



# Capacitance and its use...

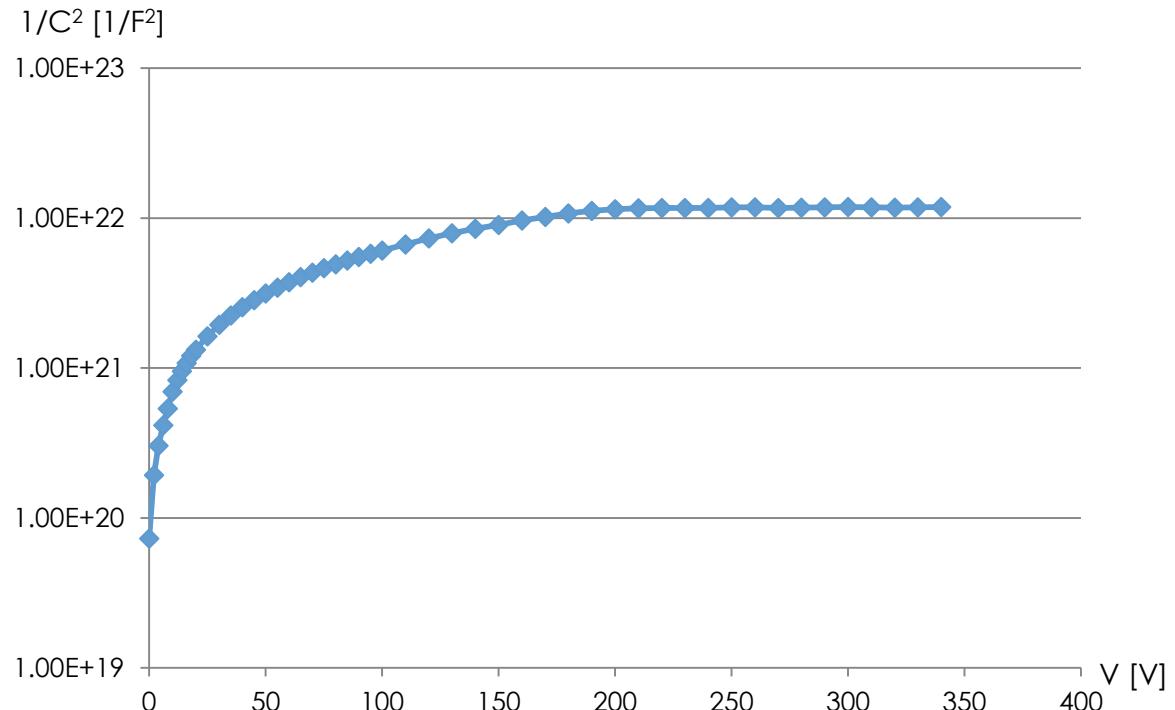
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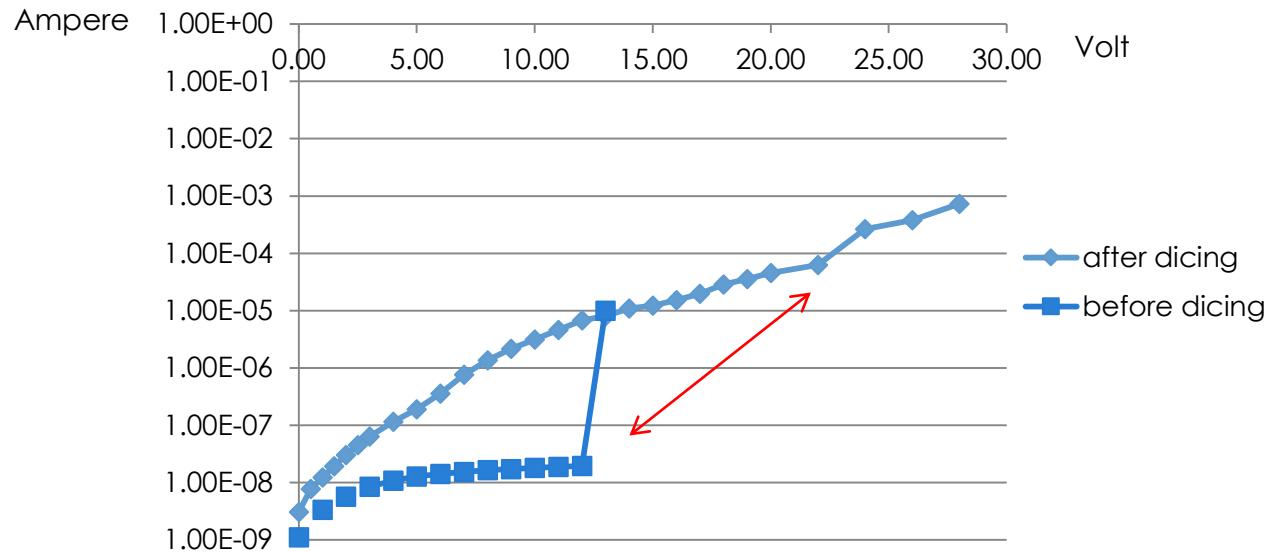
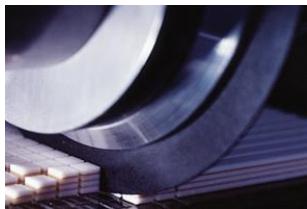
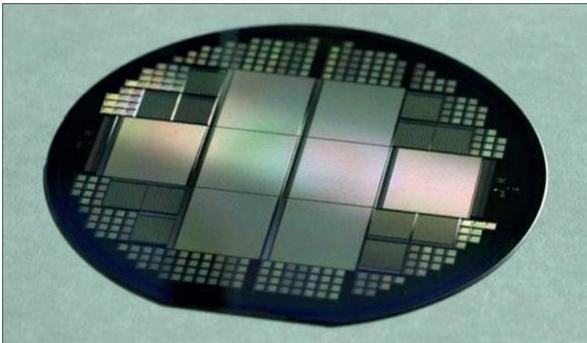
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$N_{eff}$  (effective doping concentration) can be obtained by the depletion voltage.

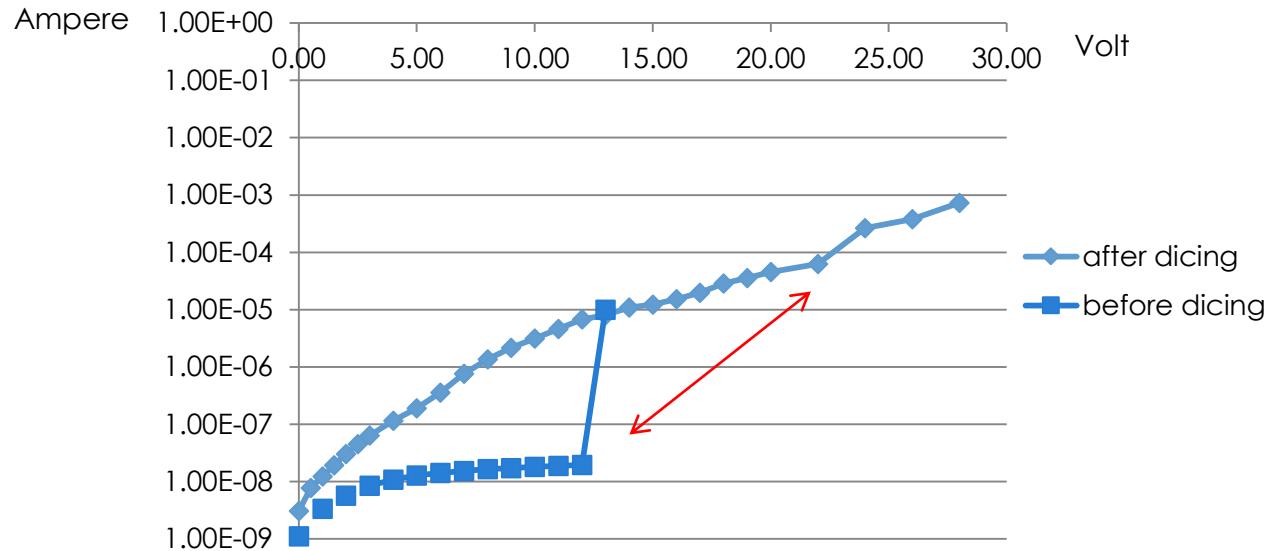
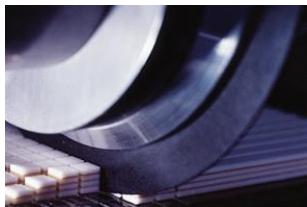
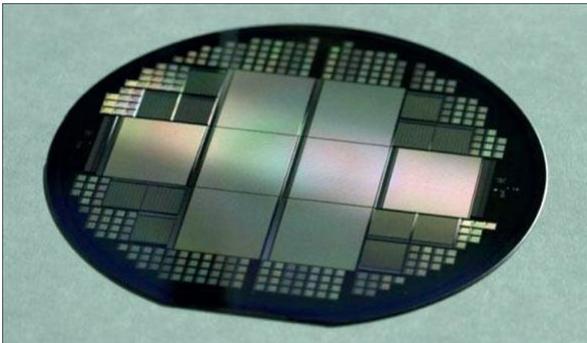
# The dicing process changes the sensor

## Measurement results



# The dicing process changes the sensor

## Measurement results



The mechanical process has changed the characteristics of the sensor.

# What's left to say

## Review

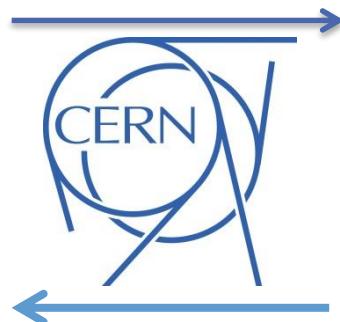


### Internship:

Warm atmosphere

CV/IV measurements  
→ Slightly monotone

Interest working field

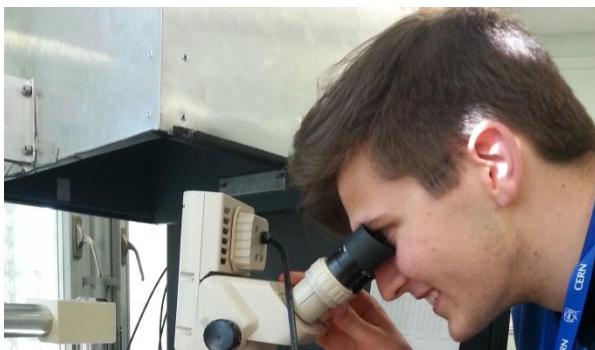


### Visits:

Right number

Interesting tours

Good view into CERN



# What's left to say

## Review

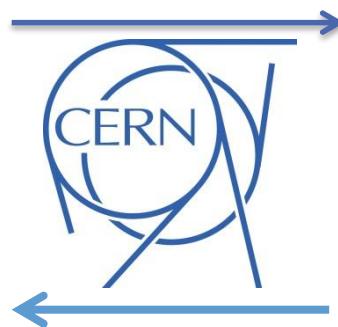


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A special thanks to the SSD-Team incl. Christian  
Laura Franconi for the CV/IV measurements &  
Sascha Schmeling for making everything possible